## SLOVENSKI STANDARD

## SIST EN 61076-5:2002

prva izdaja september 2002

Connectors with assessed quality, for use in d.c., low frequency analogue and digital high-speed data applications - Part 5: In-line sockets with assessed quality - Sectional specification (IEC 61076-5:2001)

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<u>SIST EN 61076-5:2002</u> https://standards.iteh.ai/catalog/standards/sist/4e00484b-7a26-40e6-9a61a2423fl ebe22/sist-en-61076-5-2002

ICS 31.220.10

Referenčna številka SIST EN 61076-5:2002(en)

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# EUROPEAN STANDARD

## EN 61076-5

### NORME EUROPÉENNE

### EUROPÄISCHE NORM

October 2001

ICS 31.220.10

English version

### Connectors for use in d.c., low-frequency analogue and digital high-speed data applications Part 5: In-line sockets with assessed quality -Sectional Specification (IEC 61076-5:2001)

Connecteurs pour applications Steckverbinder für Gleichspannungs- und analogiques en courant continu et Niederfrequenzanwendungen sowie basse fréquence et pour applications digitale Anwendungen mit hoher numériques utilisant des débits élevés Übertragungsrate Teil 5: In-Line-Fassungen mit bewerteter pour le transfert de données Partie 5: Supports pour microboîtiers sous Qualität -(standards.ite Rahmenspezifikation assurance de la qualité -Spécification intermédiaire (IEC 61076-5:2001) (CEI 61076-5:2001)

 
 SIST EN 61076-5:2002

 https://standards.iteh.ai/catalog/standards/sist/4e00484b-7a26-40e6-9a61a2423fl ebe22/sist-en-61076-5-2002

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Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

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# CENELEC

European Committee for Electrotechnical Standardization Comité Européen de Normalisation Electrotechnique Europäisches Komitee für Elektrotechnische Normung

### Central Secretariat: rue de Stassart 35, B - 1050 Brussels

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### Foreword

The text of document 48B/980/FDIS, future edition 1 of IEC 61076-5, prepared by SC 48B, Connectors, of IEC TC 48, Electromechanical components and mechanical structures for electronic equipment, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61076-5 on 2001-10-01.

The following dates were fixed:

-	latest date by which the EN has to be implemented at national level by publication of an identical	
	national standard or by endorsement	(dop) 2002-07-01
_	latest date by which the national standards conflicting with the EN have to be withdrawn	(dow) 2004-10-01

Annexes designated "normative" are part of the body of the standard. Annexes designated "informative" are given for information only. In this standard, annexes B and ZA are normative and annex A is informative. Annex ZA has been added by CENELEC.

### iTeh STEndorsement notice VIEW

The text of the International Standard IEC 61076-5:2001 was approved by CENELEC as a European Standard without any modification.

<u>SIST EN 61076-5:2002</u> https://standards.iteh.ai/catalo<u>g/standards/sist/</u>4e00484b-7a26-40e6-9a61a2423fl ebe22/sist-en-61076-5-2002

### Annex ZA

#### (normative)

# Normative references to international publications with their corresponding European publications

This European Standard incorporates by dated or undated reference, provisions from other publications. These normative references are cited at the appropriate places in the text and the publications are listed hereafter. For dated references, subsequent amendments to or revisions of any of these publications apply to this European Standard only when incorporated in it by amendment or revision. For undated references the latest edition of the publication referred to applies (including amendments).

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

Publication	Year	Title	<u>EN/HD</u>	Year
IEC 60068-1	1988	Environmental testing Part 1: General and guidance	EN 60068-1 <sup>1)</sup>	1994
IEC 60352	Series	Solderless connections	EN 60352	Series
IEC 60410	1973	Sampling plans and procedures for inspection by attributes D PREVI	EW	-
IEC 60512-1-100	2001	Connectors for electronic equipment)- Tests and measurements Part 1-100: General - Applicable publications	EN 60512-1-100	2001
IEC 60512-2	1985	Part 2: General examination, electrical continuity and contact resistance tests, insulation tests and voltage stress tests	-	-
IEC 60512-4	1976	Part 4: Dynamic stress tests	-	-
IEC 60512-5	1992	Part 5: Impact tests (free components), static load tests (fixed components), endurance tests and overload tests	-	-
IEC 60512-6	1984	Part 6: Climatic tests and soldering tests	-	-
IEC 60512-7	1993	Part 7: Mechanical operating tests and sealing tests	-	-
IEC 60512-8	1993	Part 8: Connector tests (mechanical) and mechanical tests on contacts and terminations	-	-
IEC 60512-9	1992	Part 9: Miscellaneous tests	-	-
IEC 60512-11	Series	Part 11: Climatic tests	EN 60512-11	Series

<sup>1)</sup> EN 60068-1 includes the corrigendum October 1988 and A1:1992 to IEC 60068-1.

indicating surface texture

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# NORME INTERNATIONALE INTERNATIONAL STANDARD

# CEI IEC 61076-5

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Connecteurs pour applications analogiques en courant continu et basse fréquence et pour applications numériques utilisant des débits élevés pour le transfert de données –

## iPartis FANDARD PREVIEW

Supports pour microboîtiers sous assurance de la qualité – Spécification intermédiaire

### SIST EN 61076-5:2002

https://standards.iteh.ai/catalog/standards/sist/4e00484b-7a26-40e6-9a61-Connectorseforstuse in 5 doc., low-frequency analogue and digital high-speed data applications –

### Part 5:

In-line sockets with assessed quality – Sectional specification

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International Electrotechnical Commission3, rue de Varembé Geneva, SwitzerlandTelefax: +41 22 919 0300e-mail: inmail@iec.chIEC web site http://www.iec.ch

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Commission Electrotechnique Internationale International Electrotechnical Commission Международная Электротехническая Комиссия



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### INTERNATIONAL ELECTROTECHNICAL COMMISSION

### CONNECTORS FOR USE IN DC, LOW-FREQUENCY ANALOGUE AND DIGITAL HIGH-SPEED DATA APPLICATIONS –

### Part 5: In-line sockets with assessed quality – Sectional specification

### FOREWORD

- 1) The IEC (International Electrotechnical Commission) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of the IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, the IEC publishes International Standards. Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. The IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of the IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested National Committees.
- 3) The documents produced have the form of recommendations for international use and are published in the form of standards, technical specifications, technical reports or guides and they are accepted by the National Committees in that sense.
- 4) In order to promote international unification, IEC National Committees undertake to apply IEC International Standards transparently to the maximum extent possible in their national and regional standards. Any divergence between the IEC Standard and the corresponding national or regional standard shall be clearly indicated in the latter.
- 5) The IEC provides no marking procedure to indicate its approval and cannot be rendered responsible for any equipment declared to be in conformity with one of its standards.
- 6) Attention is drawn to the possibility that some of the elements of this International Standard may be the subject of patent rights. The IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 61076-5 has been prepared by subcommittee 48B: Connectors, of IEC technical committee 48: Electromechanical components and mechanical structures for electronic equipment.

The text of this standard is based on the following documents:

FDIS	Report on voting
48B/980/FDIS	48B/1009/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

Annex A is for information only.

Annex B forms an integral part of this standard.

This part 5 constitutes the sectional specification in the IEC quality assessment system for electronic components (IECQ) for in-line sockets.

The QC number that appears on the cover of this publication is the specification number of the IEC Quality Assessment System for Electronic Components (IECQ).

This publication has been drafted in accordance with the ISO/IEC Directives, Part 3.

IEC 61076 consists of the following parts, under the general title, *Connectors for use in d.c., low-frequency analogue and digital high-speed data applications*:

Part 1: Generic specification

Part 2: Circular connectors with assessed quality - Sectional specification

Part 3: Rectangular connectors with assessed quality – Sectional specification

Part 4: Printed board connectors with assessed quality - Sectional specification

Part 5: In-line sockets with assessed quality - Sectional specification

Part 6: Loose part contacts with assessed quality - Sectional specification 1)

Part 7: Cable outlet accessories with assessed quality, including qualification and capability approval – Sectional specification

The committee has decided that the contents of this publication will remain unchanged until 2005. At this date, the publication will be TANDARD PREVIEW

reconfirmed;withdrawn;

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- replaced by a revised edition, or
- amended.

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<sup>&</sup>lt;sup>1)</sup> Under consideration.

### CONNECTORS FOR USE IN DC, LOW-FREQUENCY ANALOGUE AND DIGITAL HIGH-SPEED DATA APPLICATIONS –

### Part 5: In-line sockets with assessed quality – Sectional specification

#### 1 Scope and object

This part of IEC 61076 relates to the plug-in sockets designed for in-line electronic packages of assessed quality. Sockets covered by this specification are devices which provide a means of interchangeability between devices and compliance between mating limits.

The scope of this specification covers sockets for packages with contacts having one of the following in-line formats.

- a) Single in-line sockets.
- b) Dual in-line sockets.
- c) Quad in-line sockets.
- d) Zig-zag in-line (staggered) sockets.

The object of this specification is to define (standards.iteh.ai)

- a unified numbering system;
- functional levels and standard tests methods 6 and 0 gauges for use in the examination of these sockets; https://standards.iteh.ai/catalog/standards/sist/4e00484b-7a26-40e6-9a61-
- appropriate reference dimensions of the mating device and board layout to establish intermateability and interchangeability criteria. Test severity and performance requirements prescribed in detail specifications referring to this sectional specification shall be equal to, or greater than, those specified herein; degradations are not permitted.

#### 2 General

#### 2.1 Normative references

The following normative documents contain provisions which, through reference in this text, constitute provisions of this part of IEC 61076. For dated references, subsequent amendments to, or revisions of, any of these publications do not apply. However, parties to agreements based on this part of IEC 61076 are encouraged to investigate the possibility of applying the most recent editions of the normative documents indicated below. For undated references, the latest edition of the normative document referred to applies. Members of IEC and ISO maintain registers of currently valid International Standards.

IEC 60068-1:1988, Environmental testing – Part 1: General and guidance

IEC 60352 (all parts), Solderless connections

IEC 60410:1973, Sampling plans and procedures for inspection by attributes